

Notice of References Cited	Application/Control No. 10/779,779	Applicant(s)/Patent Under Reexamination NIIYA, HIROTAKA	
	Examiner W. Patty Chen	Art Unit 2871	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0109811	08-2002	Park et al.	349/113
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	M	US-			

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NON-PATENT DOCUMENTS

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